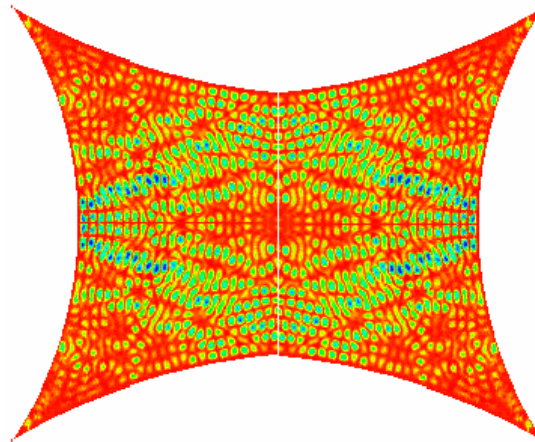




Prediction and measurement of induced voltages inside complicated enclosures using wave-chaos

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Thomas M. Antonsen Jr., Edward Ott, Steven M. Anlage



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Motivation :- The “Four Famous” Questions:

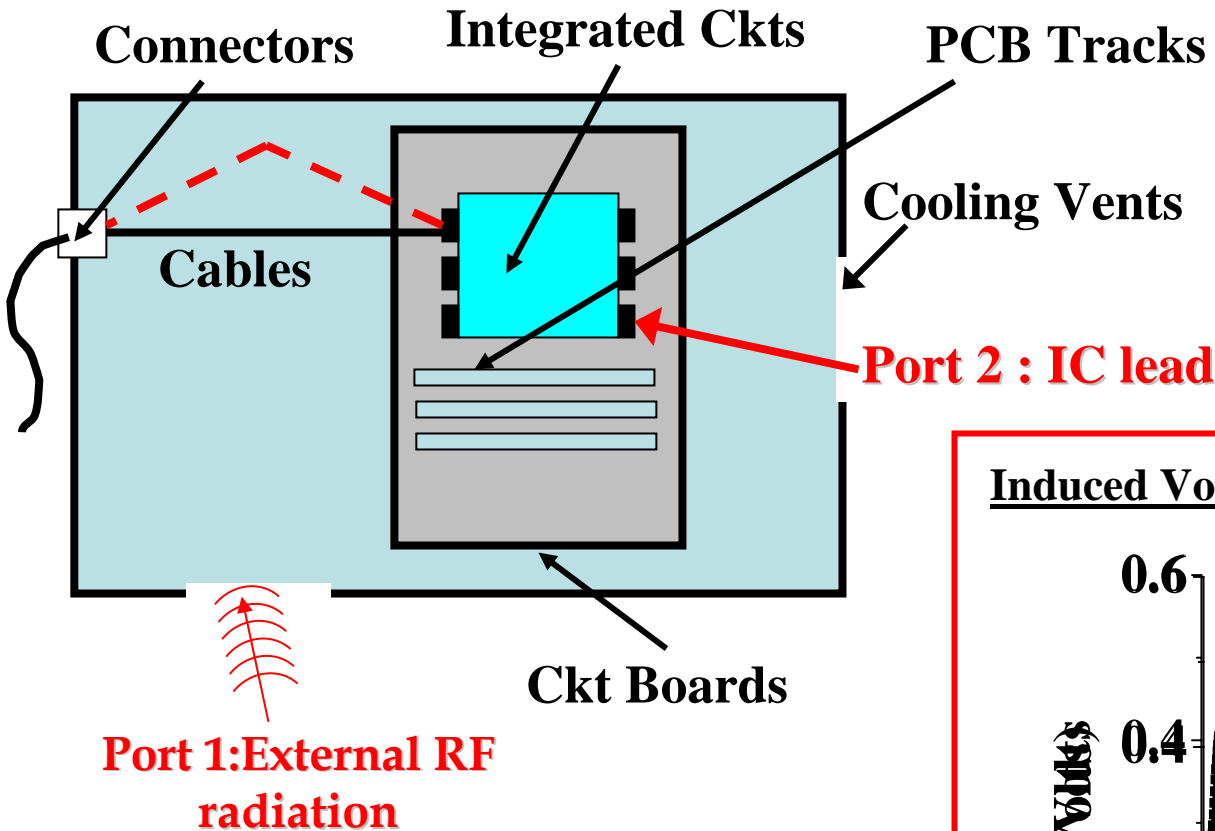
- Is there some fast, simple and accurate way to predict the voltages induced at specific points within a complicated metallic enclosure (e.g. computer-box) due to external radiation?

- What factors determine the nature of these induced voltages ?

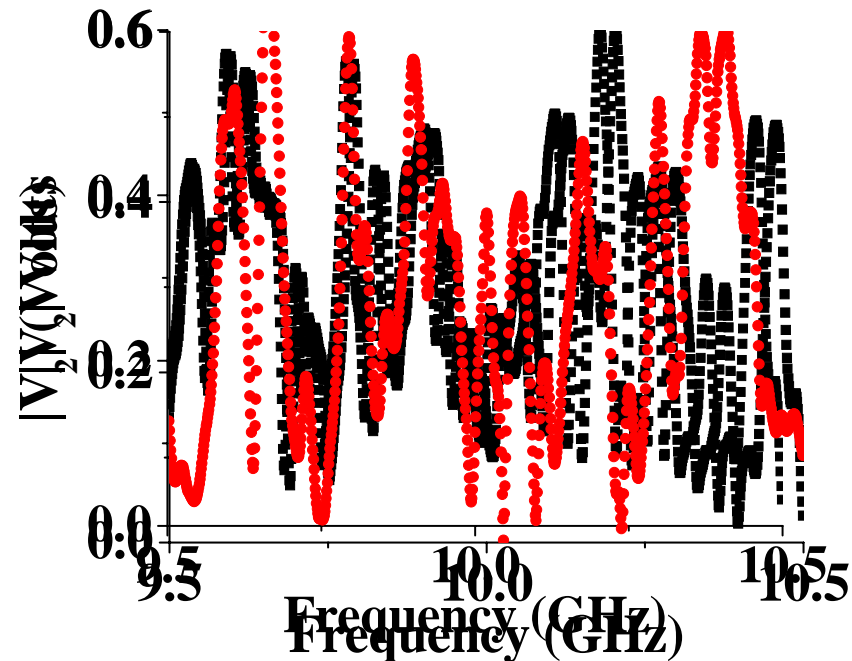
- Is there some “optimally shaped” wave-form for the external radiation, for which the electronics within the enclosure is most susceptible ?

- Is it possible to engineer an enclosure to make it resistant to HPM attack ?

1. Can we predict the voltages induced at specific locations in a computer-box due to a external RF radiation?



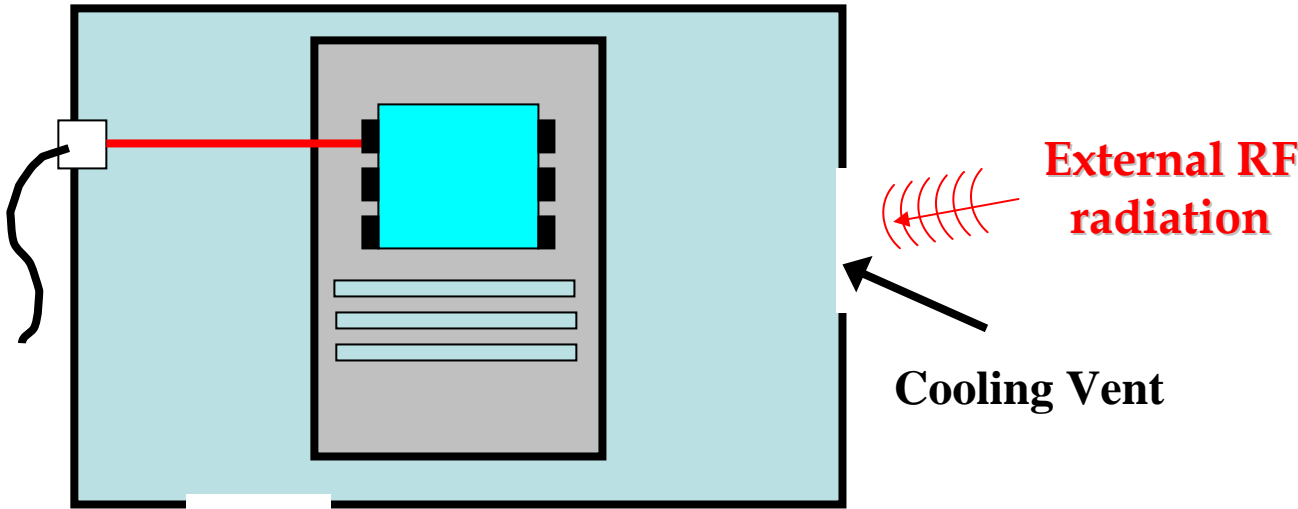
Induced Voltages at port 2 in a computer-box



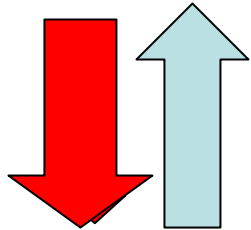
• Extreme sensitivity to system details makes numerical EM solutions based on Maxwell's equations impractical.

• Use Statistical Description !!

Our outlook to this problem:- Formulating the Random Coupling Model

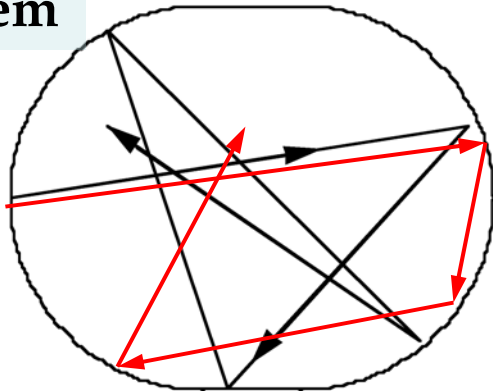


Treat the computer-box as a wave-chaotic system



- Use Universal Properties of Wave Chaotic Systems to predict induced voltage distributions at specific locations inside the enclosure.

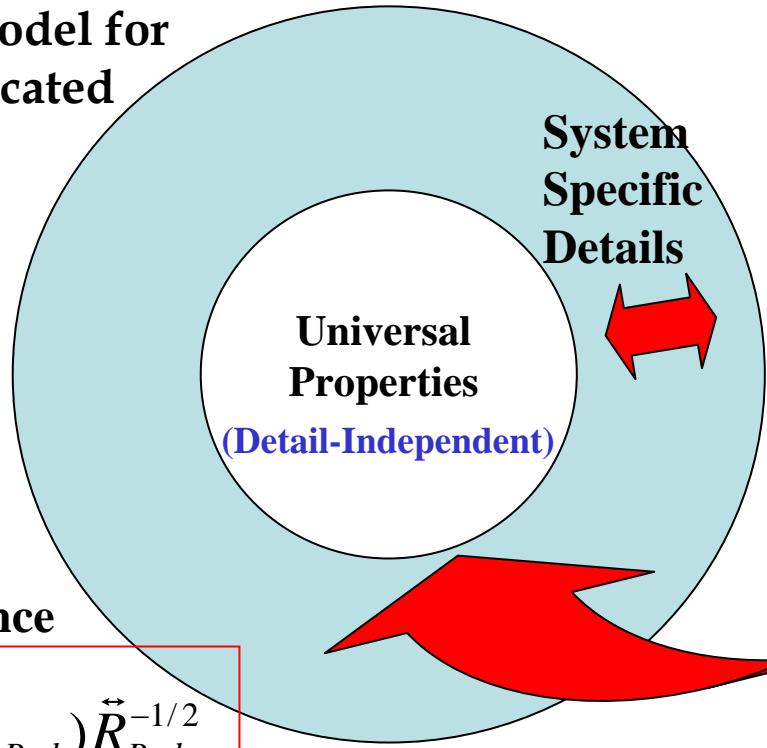
Chaotic Ray Trajectories



Random Coupling Model (RCM)- “In a Nut Shell”

Electromagnetics, **26**, 3 (2006).
Electromagnetics, **26**, 37 (2006).
Zheng, Antonsen, Ott

- RCM: Stochastic model for impedance of complicated enclosures



Real-World Data on complicated enclosures

Normalized impedance

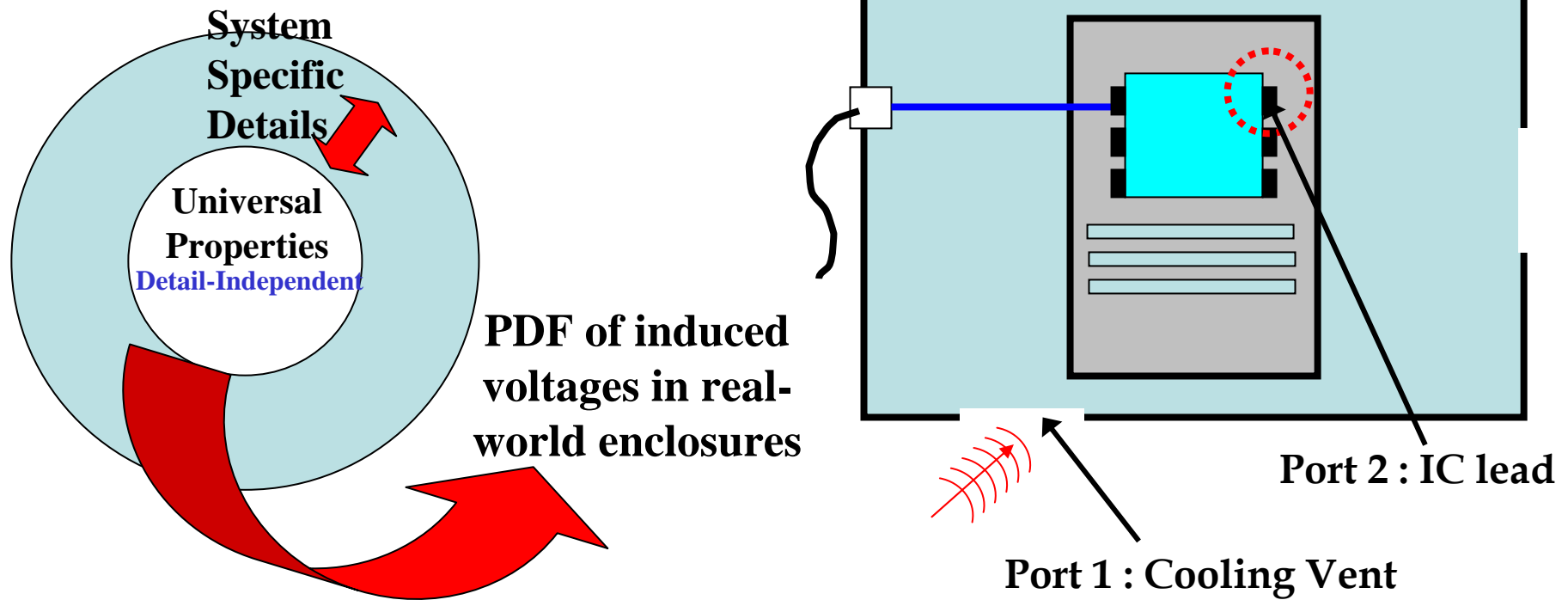
$$\vec{z} = \vec{R}_{Rad}^{-1/2} (\vec{Z}_{Cavity} - j\vec{X}_{Rad}) \vec{R}_{Rad}^{-1/2}$$

Radiation Impedance

- Statistical Description of normalized impedance depends **only** on a dimensionless “loss-parameter”

$$\alpha = \frac{k^2}{\Delta k_n^2 Q}$$

Implications of RCM to Real-world 3D cavities

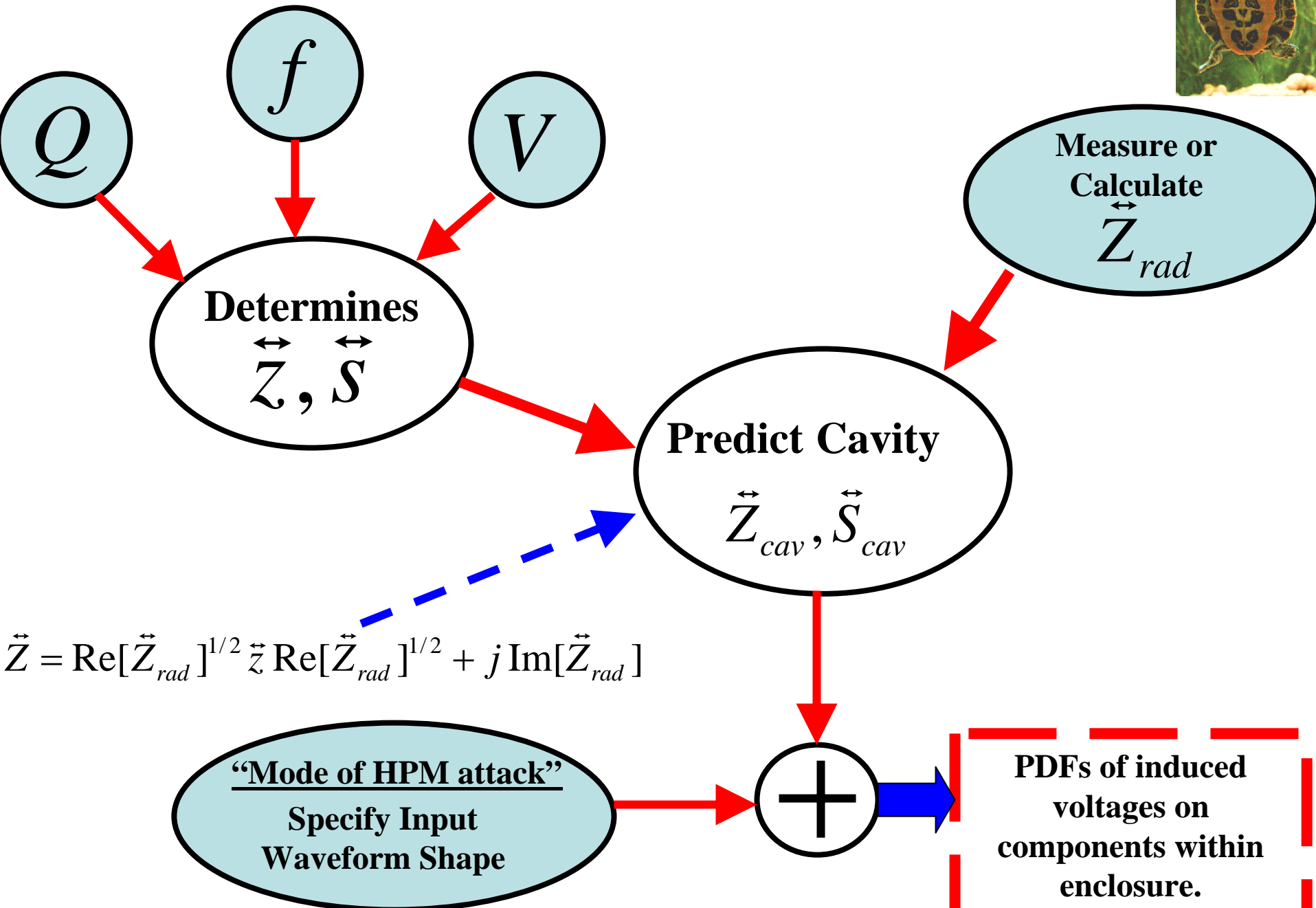


2. What minimum information do I need to predict the range of voltages on port 2 because of 'x' watts of power injected into port 1?

Minimum Information to predict PDF of induced voltages at port 2:

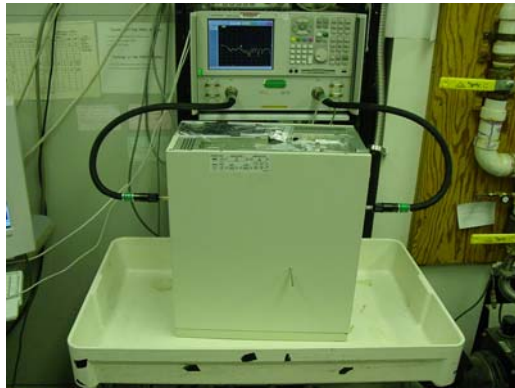
Frequency, Volume Losses } α } Determine the shape and scales of the induced voltage PDFs
Radiation impedance of the ports }
Radiated power Wave-form from port 1 }

“Terrapin algorithm” for *a priori* prediction of Induced Voltage PDFs

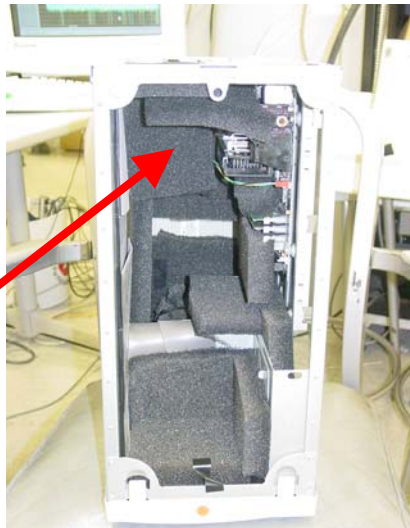


“3D Real-World” Test of the Random Coupling Model and the “Terrapin Algorithm”

- Frequency Range: 2GHz to 20 GHz ($\lambda \ll L$)
- Ensemble Averaging over ~20 positions of the mode-stirrer.

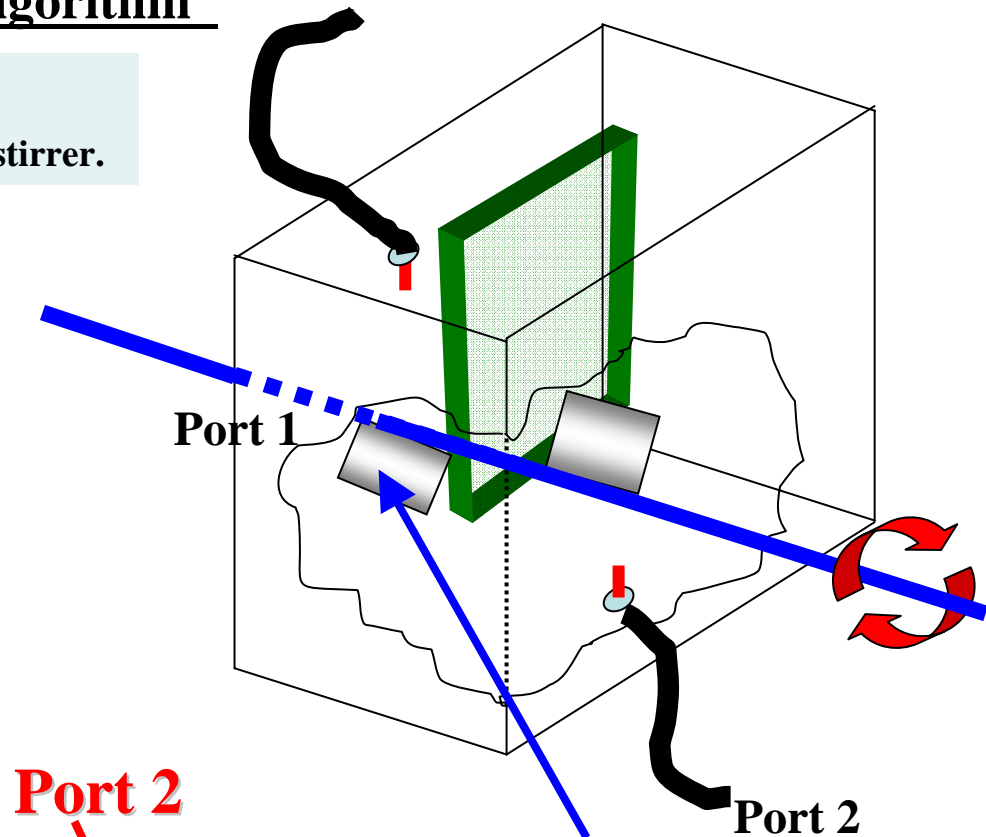


Experimental Setup [Cavity Case]



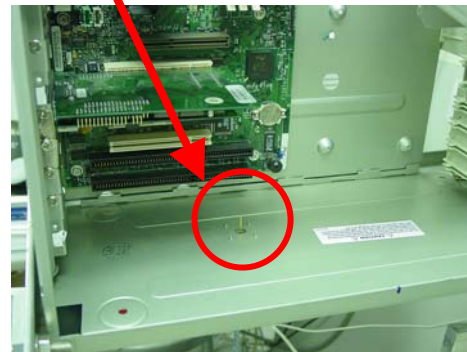
Microwave absorber

Port Radiation Measurement Setup

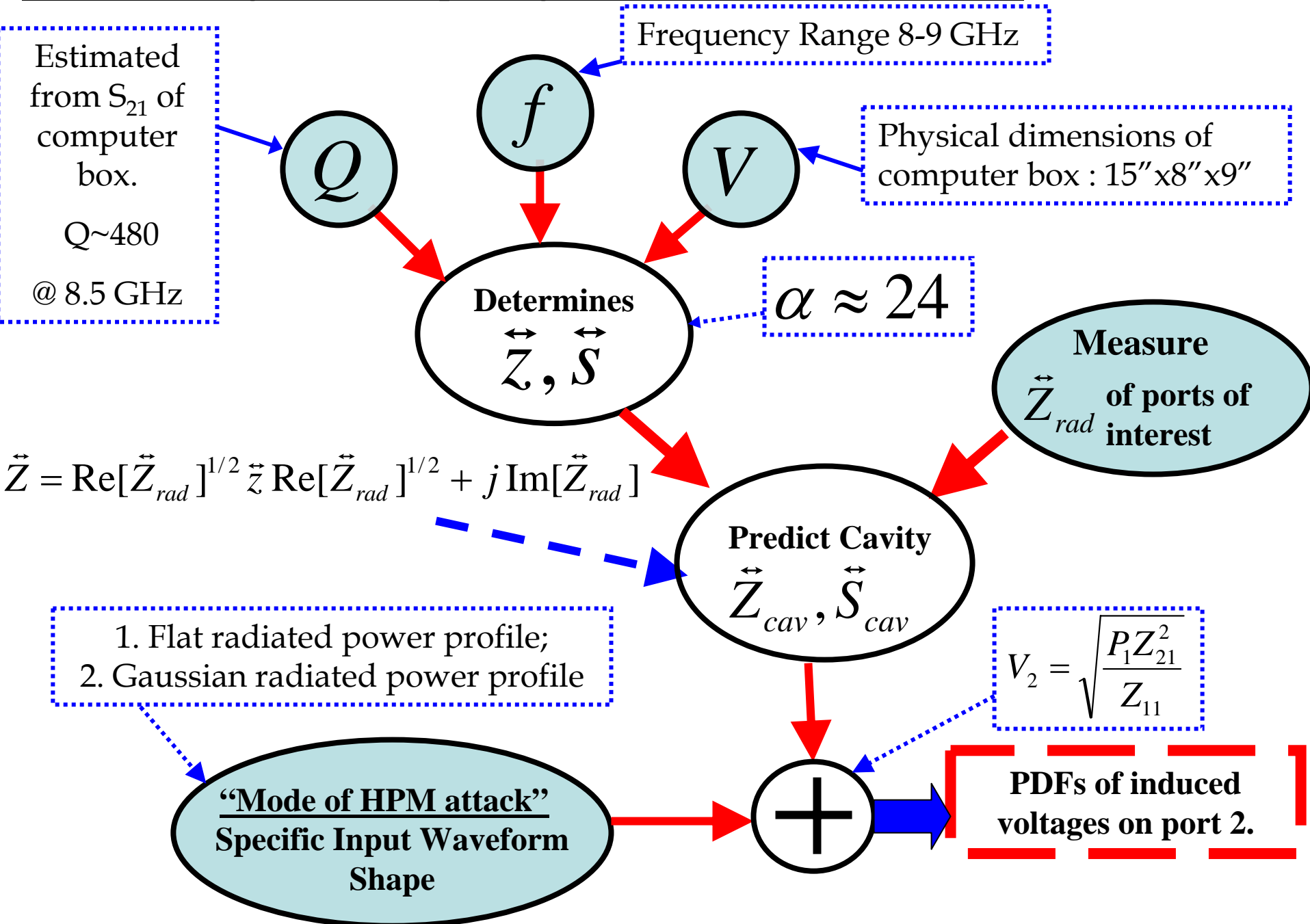


Port 2

Paddle-Wheel Mode-Stirrer

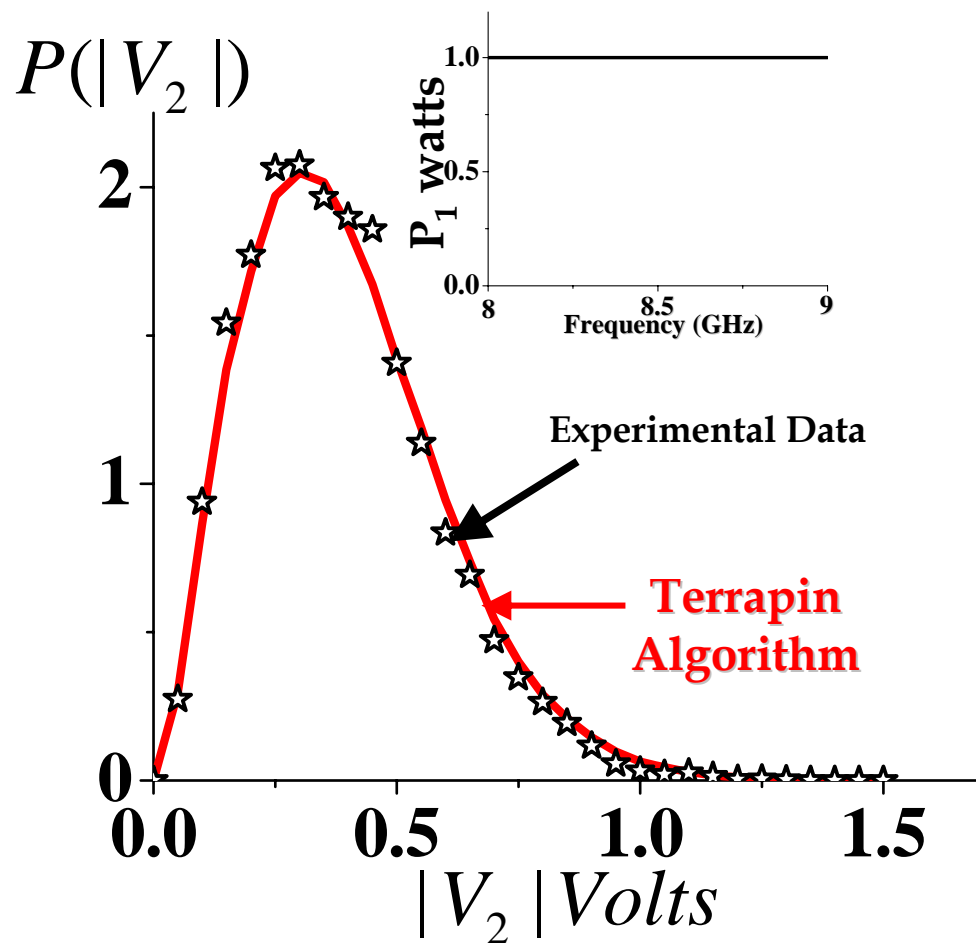


Tutorial: Using the “Terrapin Algorithm” on the computer-box:

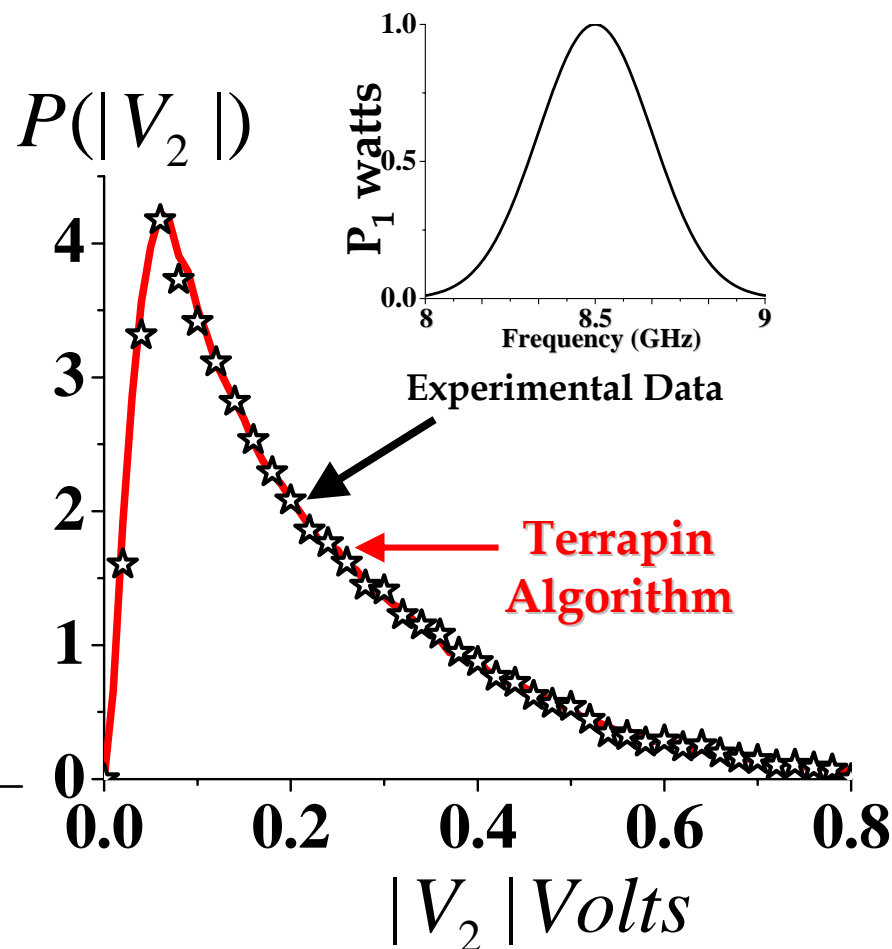


PDF of induced voltages on port 2 of computer-box for different power profiles radiated from Port 1

Flat power-profile
radiated from port 1



Gaussian-shaped power-profile
radiated from port 1

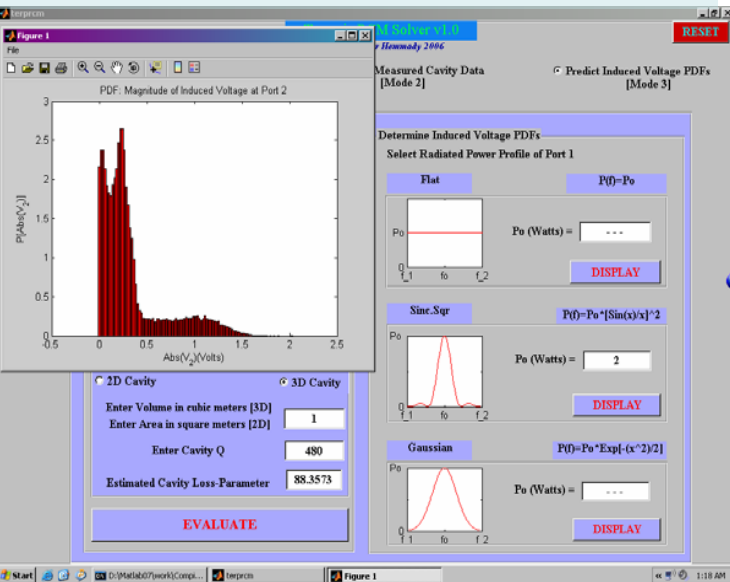


For the End-User : Terrapin RCM Solver v1.0

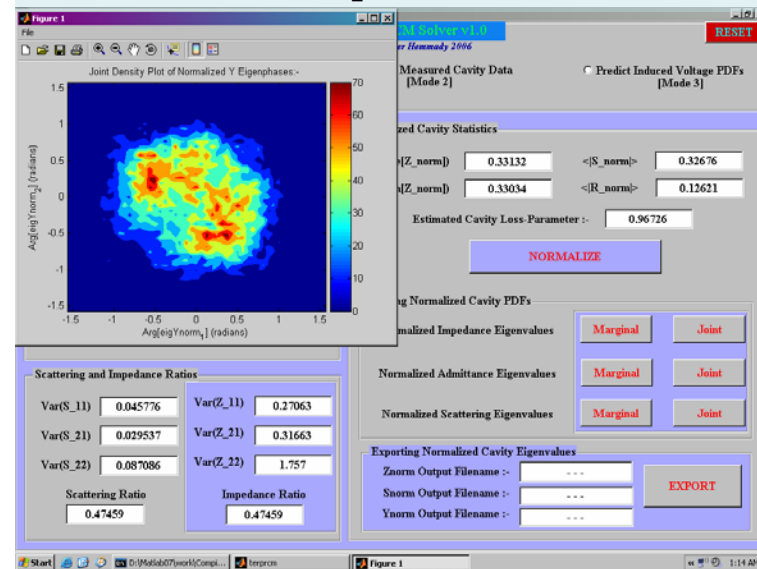
- User-friendly, stand-alone, GUI code using RCM
- Current Capabilities- **Typical run-time ~ 5 to 15 mins**
 - Predict induced voltages in real-world, complicated 2D/3D enclosures with minimum of user-inputs
 - Determine universal fluctuations in user-supplied data on real-world 2D/3D enclosures
 - Generate universal PDFs for user-specified α
- www.csr.umd.edu/anlage/RCM/index.htm



Screenshots- Terrapin RCM Solver v1.0



Screenshots- Terrapin RCM Solver v1.0



Conclusions: Extensively validated RCM for 2D/3D cavities. IT WORKS!!

- Is there some fast, simple, accurate way to determine *a priori* the voltages induced at specific points within a complicated metallic enclosure (computer-box) due to external radiation?

Use a Statistical Description (RCM).

www.csr.umd.edu/anlage/RCM/index.htm

- What factors determine the nature of these induced voltages ?

Frequency, Volume of Enclosure, Typical Q of Enclosure,

Radiation Impedance of ports, shape of external radiation wave-form

- Is there some “optimally shaped” waveform for the external radiation, for which the internal electronics is most susceptible ?

See talks by Dr. Steven Anlage ; Dr. John Rodgers to follow.....

“Terrapin Algorithm” : quick insight into induced voltages for given excitation

- Is it possible to engineer an enclosure to make it resistant to HPM attack ?

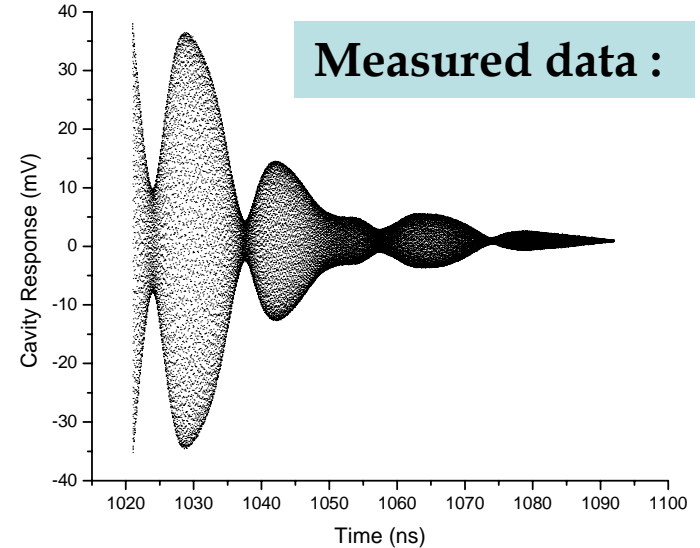
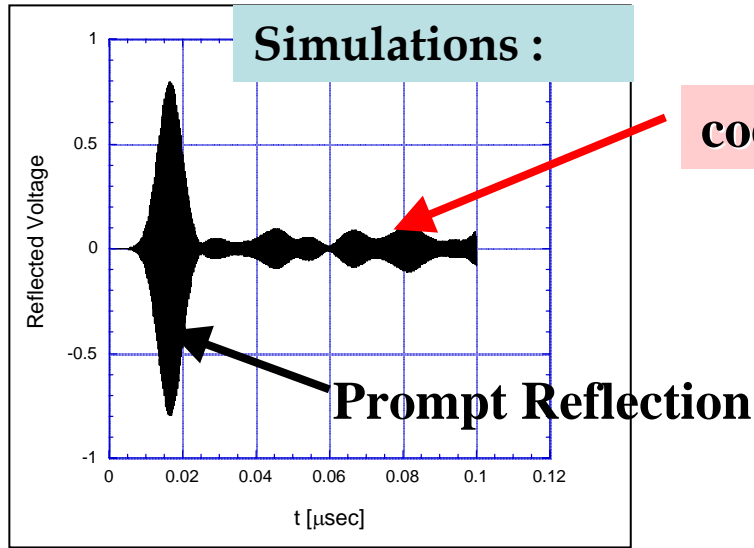
Higher α =>
more resistant.

Radiation Impedance
Engineering

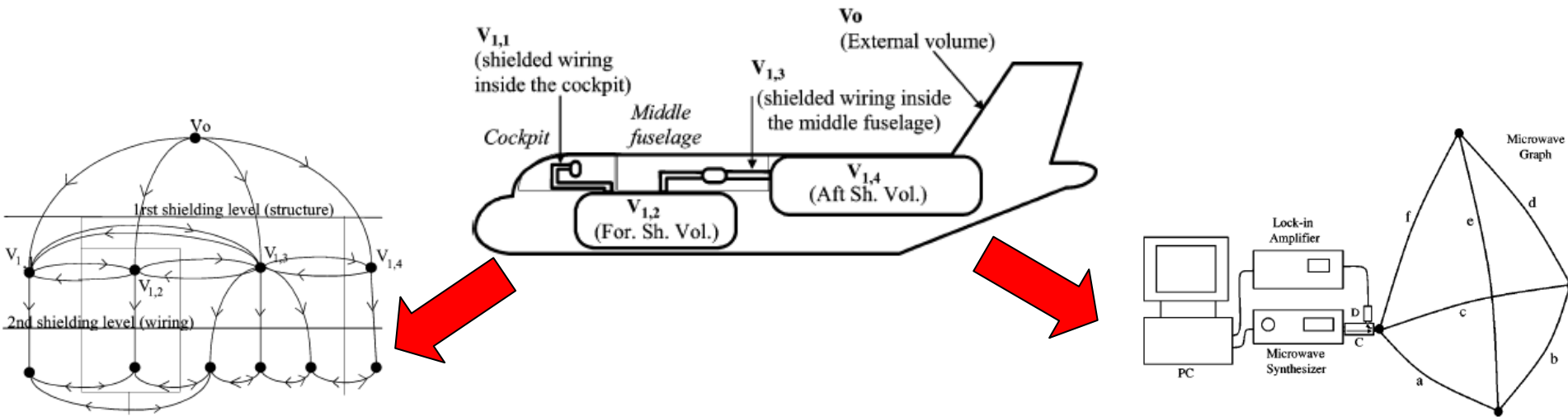
Non-Reciprocal Media
(Ferrites)

Future Work:

- Time Domain RCM theory / Experiments: (Hart, Bertrand, Antonsen, Ott, Anlage)



- Quantum Graphs and its applications to EMC topology:



Publication List: www.csr.umd.edu/anlage/RCM/index.htm

1. S.Hemmady, *et. al.* “Experimental test of Universal Conductance Fluctuations by means of Wave-Chaotic Microwave Cavities”- **cond-mat/0606650 (submitted to Phys. Rev. B-RC).**
2. S.Hemmady, *et. al.* “Universal Impedance, Admittance and Scattering Fluctuations of wave-chaotic systems”- **cond-mat/0501231 (submitted to Phys. Rev. E).**
3. S.Hemmady, *et. al.* “Universal Impedance Fluctuations in Wave-Chaotic Systems”
Phys. Rev. Lett. 94, 014102 (2005).
4. S.Hemmady, *et. al.* “Universal Statistics of the Scattering Coefficient of Chaotic Microwave Cavities”- **Phys. Rev. E. 71, 056215 (2005).**
5. S.Hemmady, *et. al.* “Aspects of the Scattering and Impedance Properties of Chaotic Microwave Cavities”- **Acta Physica Polonica A 109, 65 (2006).**
6. X. Zheng, *et. al.* “ Characterization of Fluctuations of Impedance and Scattering Matrices in Wave-Chaotic Systems”- **Phys. Rev. E. 73, 046208 (2006).**
7. T.M Antonsen , *et. al.* “Statistical Model for Scattering Matrices of Open Cavities”
URSI EMTS 2004 825-827 (2004).

Random Coupling Model Publications:

1. X. Zheng, T.M.Antonsen, and E. Ott –Electromagnetics, **26**, 3 (2006).
2. X. Zheng, T.M.Antonsen, and E. Ott –Electromagnetics, **26**, 37 (2006).

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